



Contribution ID: 7

Type: **not specified**

Recent Results with Ultra-Fast Silicon Detectors

The performance of Ultra-fast Silicon Detectors (UFSD) has been measured pre-rad and after neutron irradiation up to $6 \times 10^{15} \text{ n/cm}^2$.

Of special interest are UFSD with 35 and 50 micron thickness.

The measured time resolution is traced back to the evolution with fluence of internal gain, rise time and noise.

Primary author: SADROZINSKI, Hartmut (University of California,Santa Cruz (US))

Presenter: SADROZINSKI, Hartmut (University of California,Santa Cruz (US))